

Evaluating the Duplication of Dual-Rail Logics on FPGAs

Alexander Wild, Amir Moradi, Tim Güneysu

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Motivation

Dual-rail precharge logic

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Dual-rail logic

- Differential encoding
- Valid values: 10 or 01
- No inverter

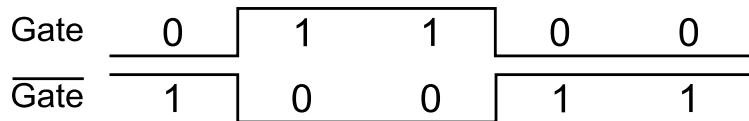
Gate	0	1	1	0	0
$\overline{\text{Gate}}$	1	0	0	1	1

Motivation

Dual-rail precharge logic

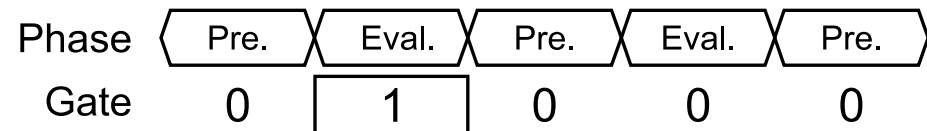
Dual-rail logic

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Precharge logic

- Alternates between precharge and logic value
 - Precharge phase
 - Evaluation phase

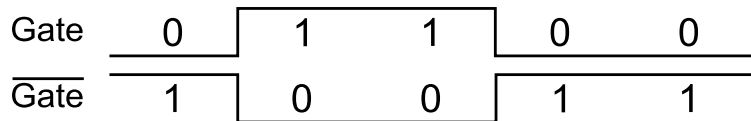


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Dual-rail precharge logic

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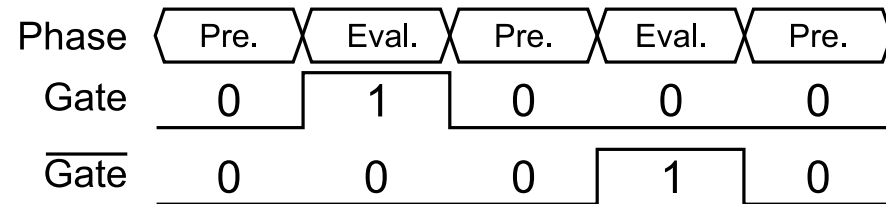
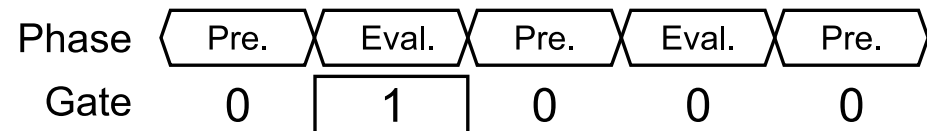


Dual-rail precharge logic

- Differential encoding
 - Precharge phase: 00 or 11
 - Evaluation phase 01 or 10
- One transition per phase

Precharge logic

- Alternates between precharge and logic value
 - Precharge phase
 - Evaluation phase

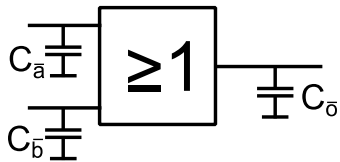
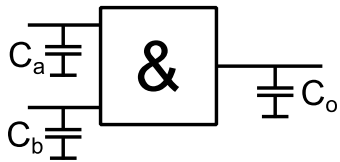


Motivation

Pitfalls

Signal delays/capacitance

- Different signal routings.

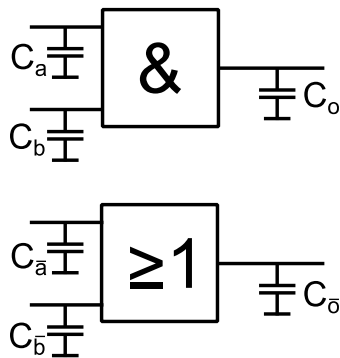


Motivation

Pitfalls

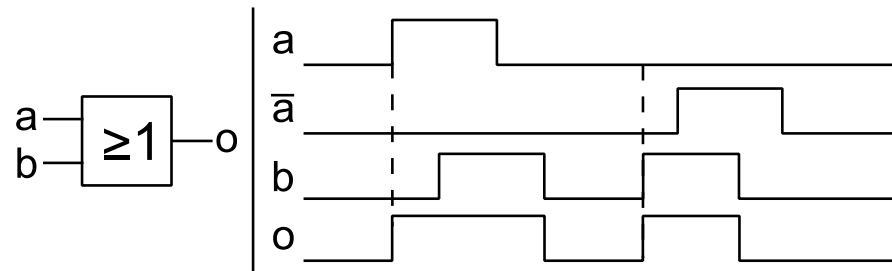
Signal delays/capacitance

- Different signal routings.



Early Evaluation

- Transition based on the arriving signals.
- Different and data-dependent point of evaluation.



Motivation

Logic Styles

Motivation

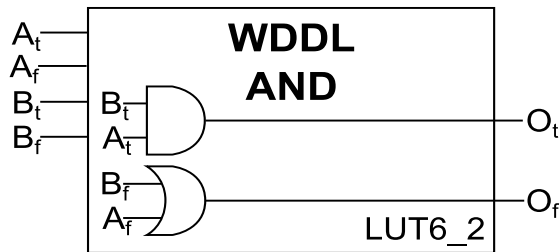
Logic Styles

WDDL

K. Tiri and I. Verbauwhede

DATE'04

- No Glitches



Motivation

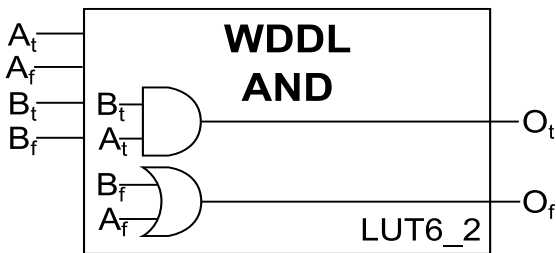
Logic Styles

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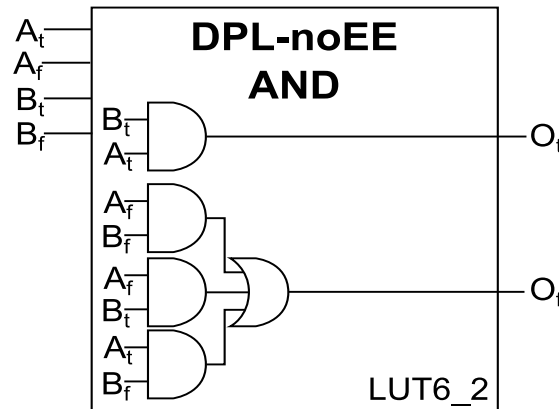


DPL-noEE

S. Bhasin et al.

WESS'10

- No Glitches
- No Early Evaluation



Motivation

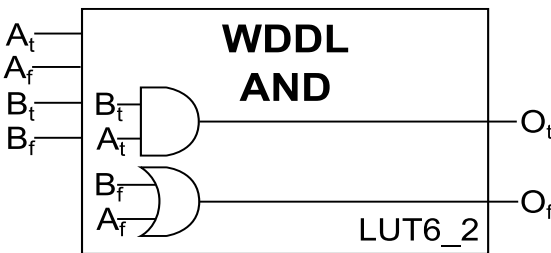
Logic Styles

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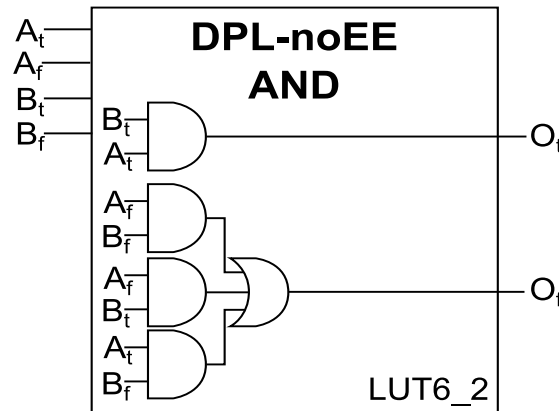


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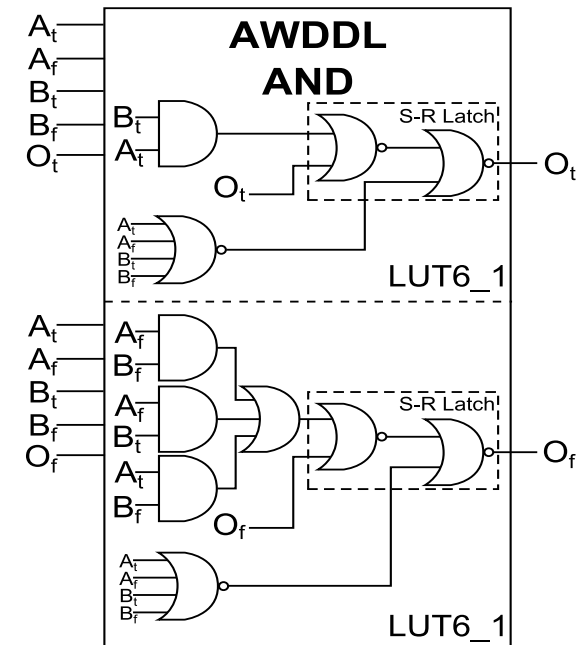


AWDDL

A. Moradi and V. Immler

CHES'14

- No Glitches
- No Early Propagation



Motivation

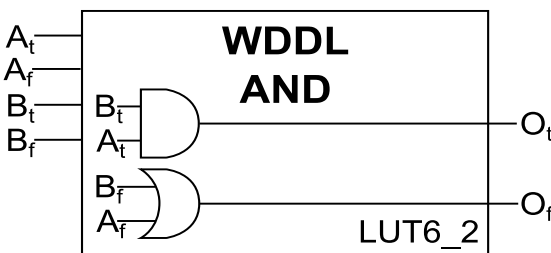
Logic Styles

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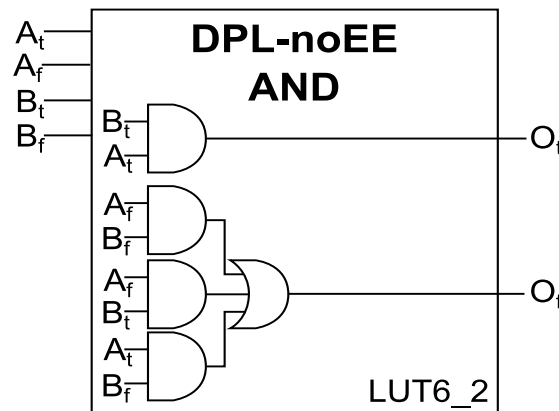


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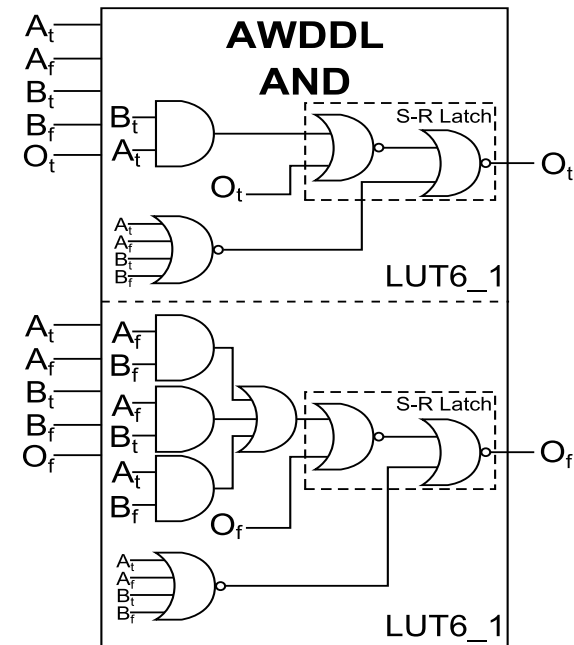


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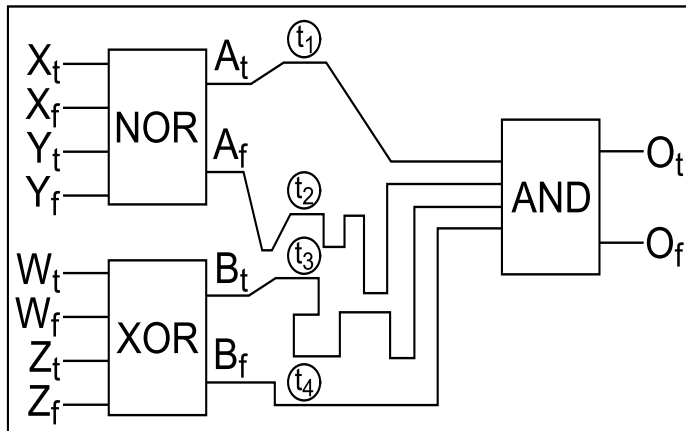
Wire Capacities / Routing imbalances!

Motivation

Duplication

DWDDL

P. Yu, P. Schaumont CODES+ISSS'07

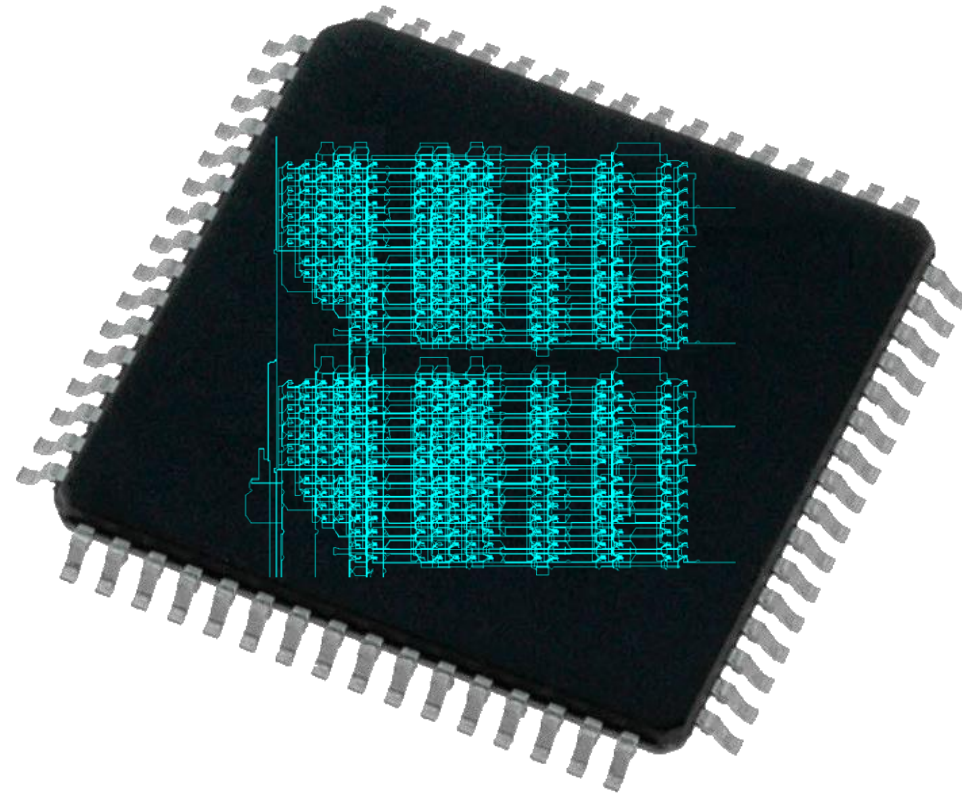
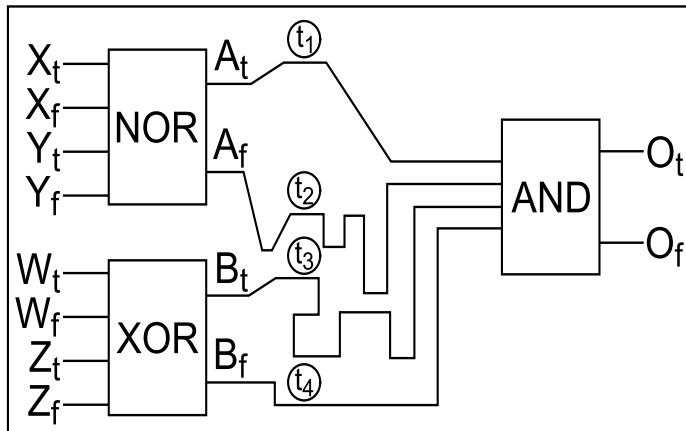
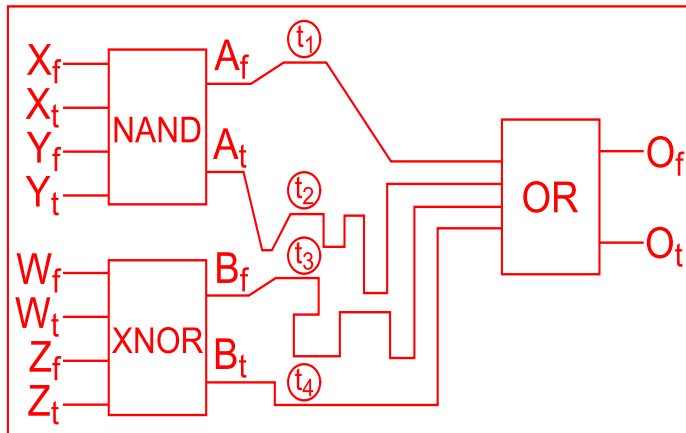


Motivation

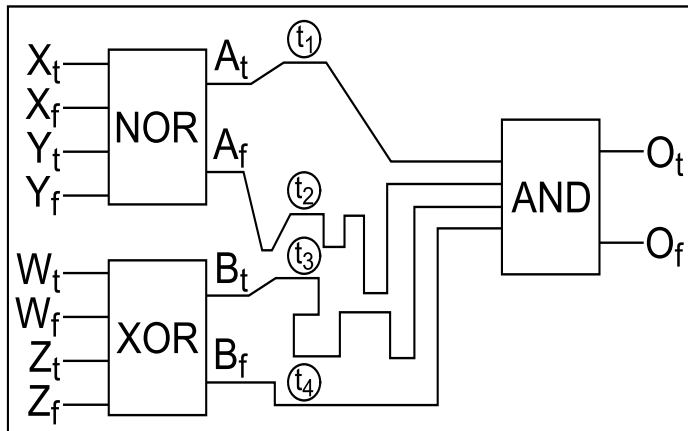
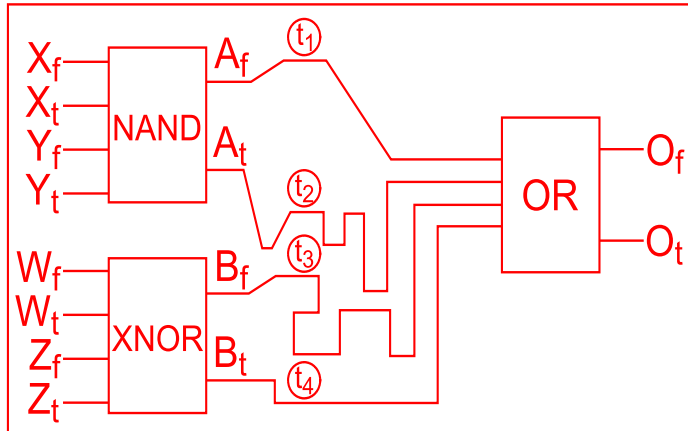
Duplication

DWDDL

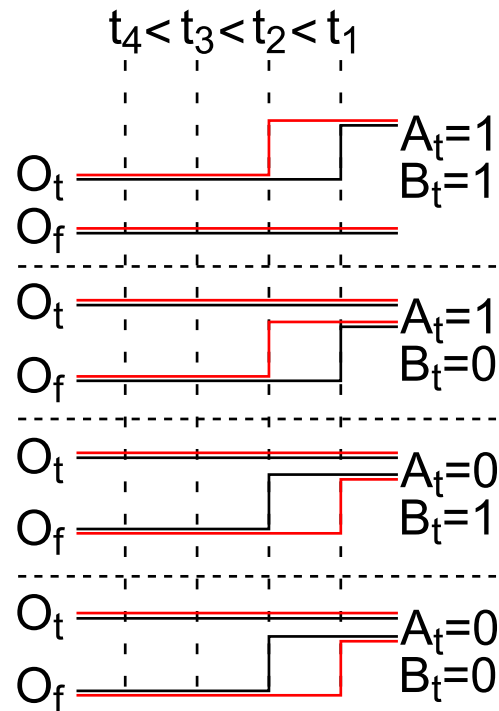
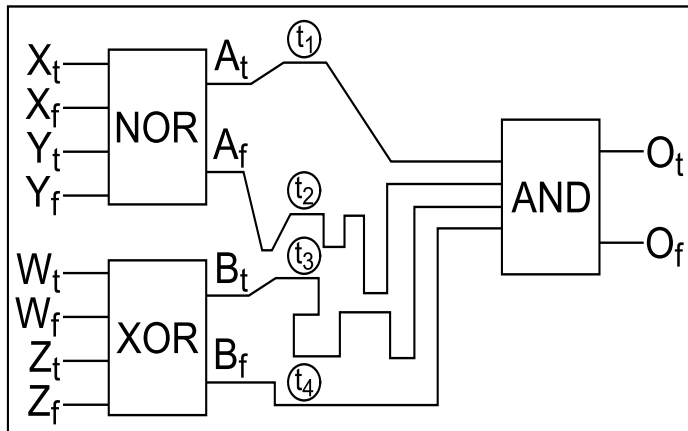
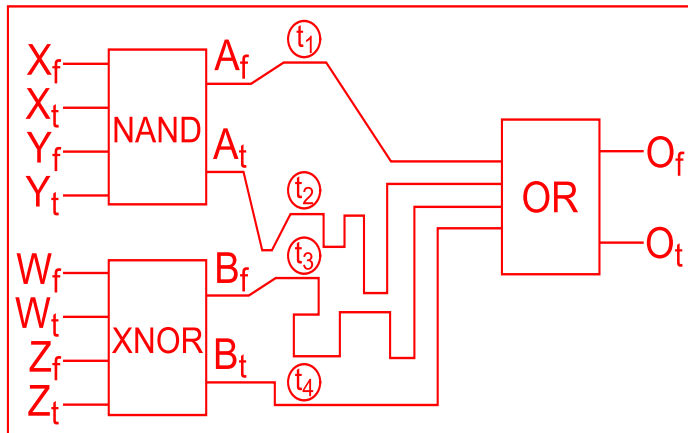
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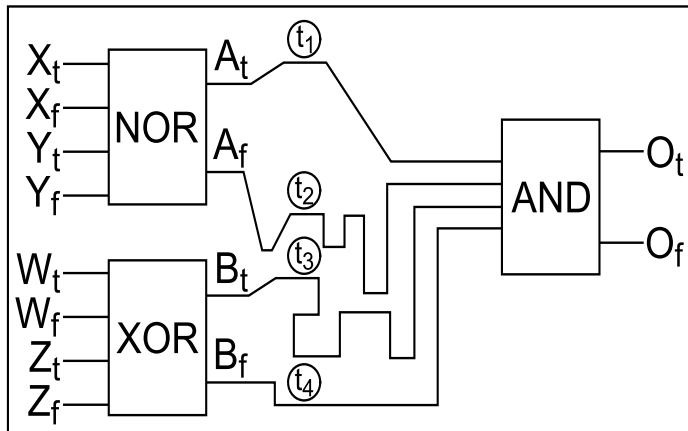
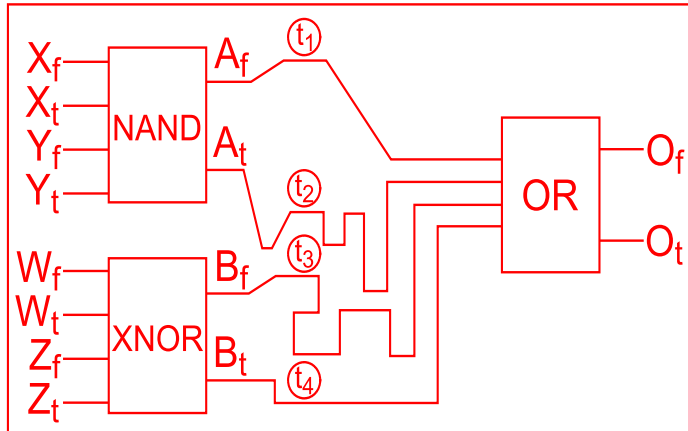
Data-Dependent Time of Evaluation



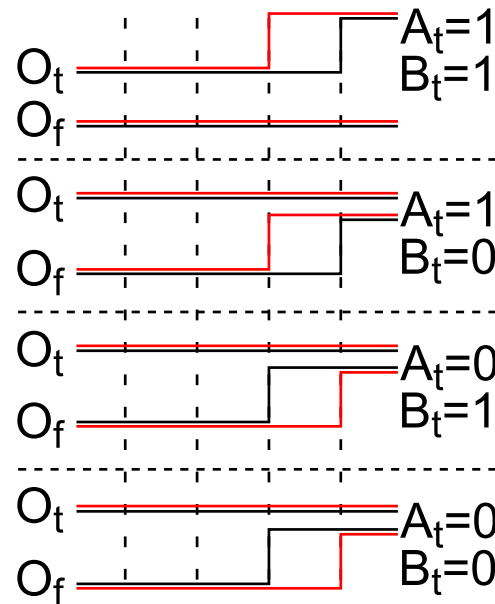
Data-Dependent Time of Evaluation



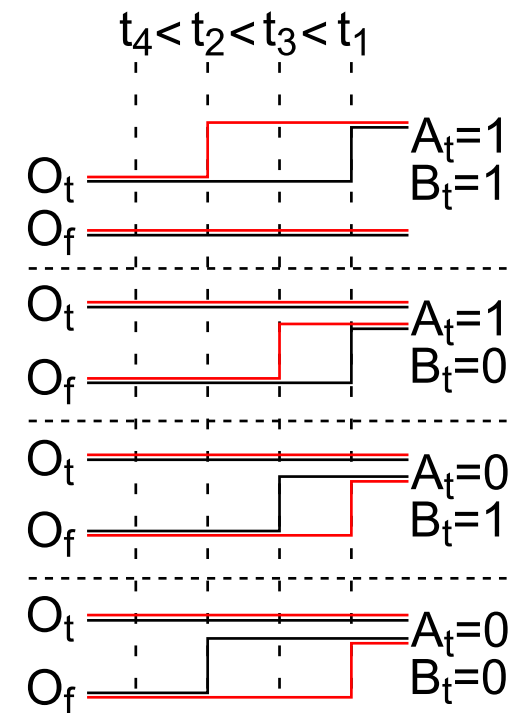
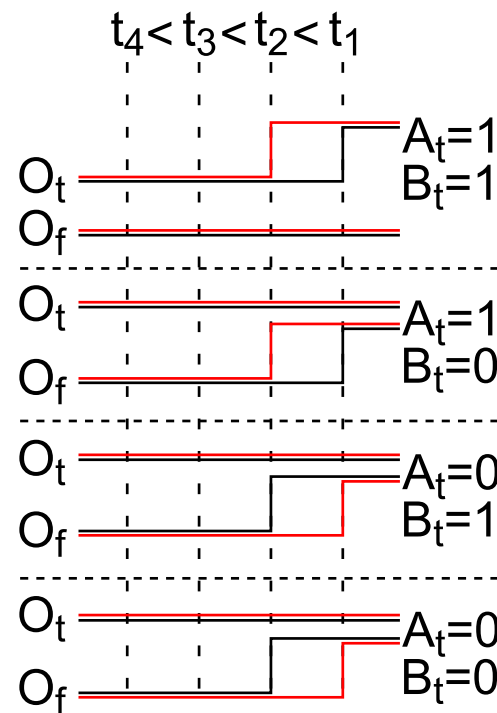
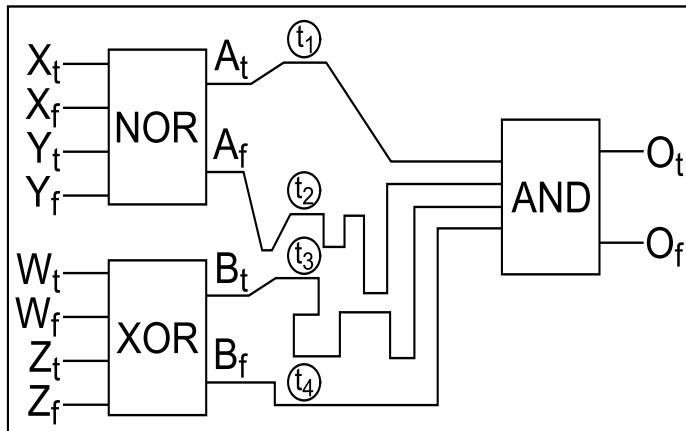
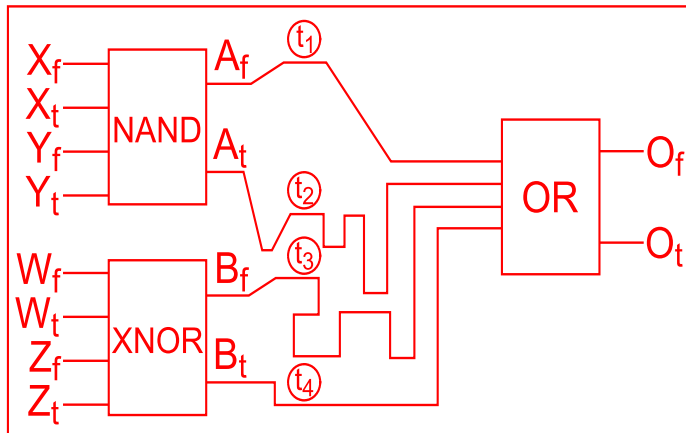
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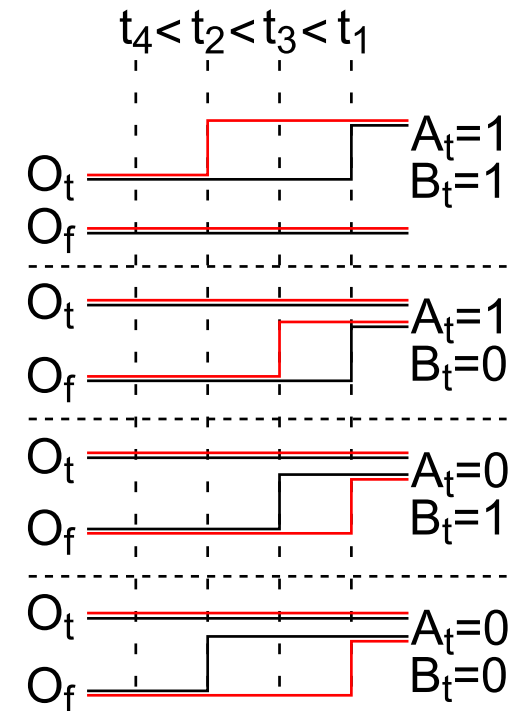
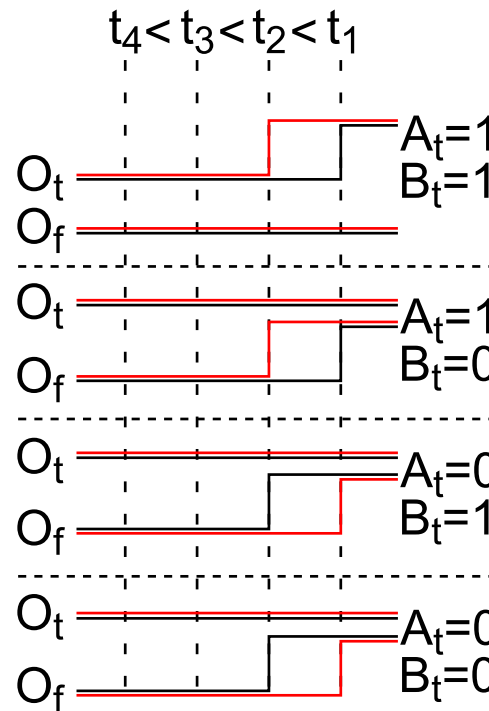
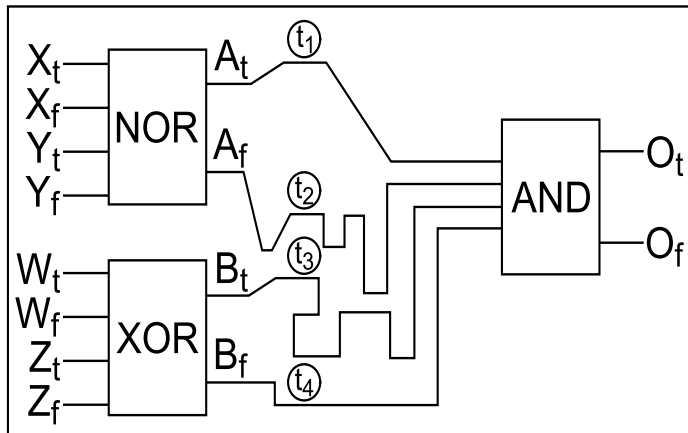
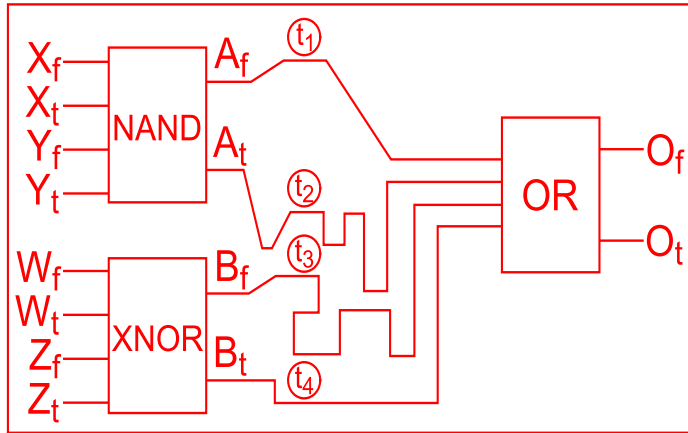
$$t_4 < t_3 < t_2 < t_1$$



Data-Dependent Time of Evaluation

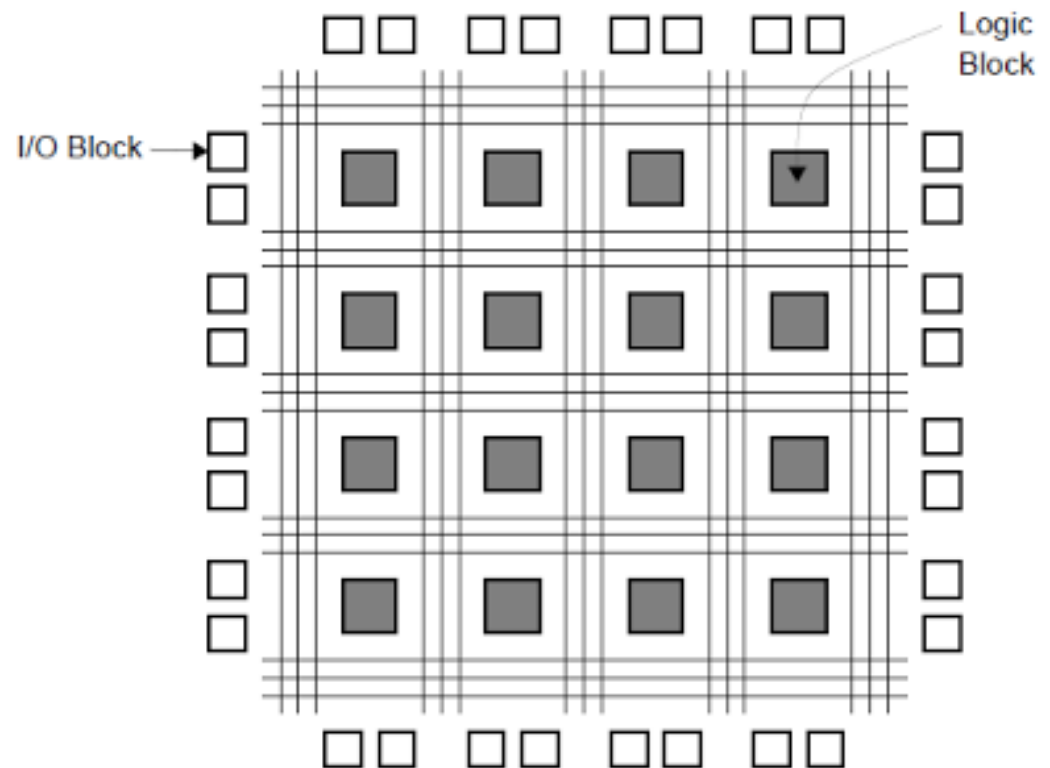


Data-Dependent Time of Evaluation



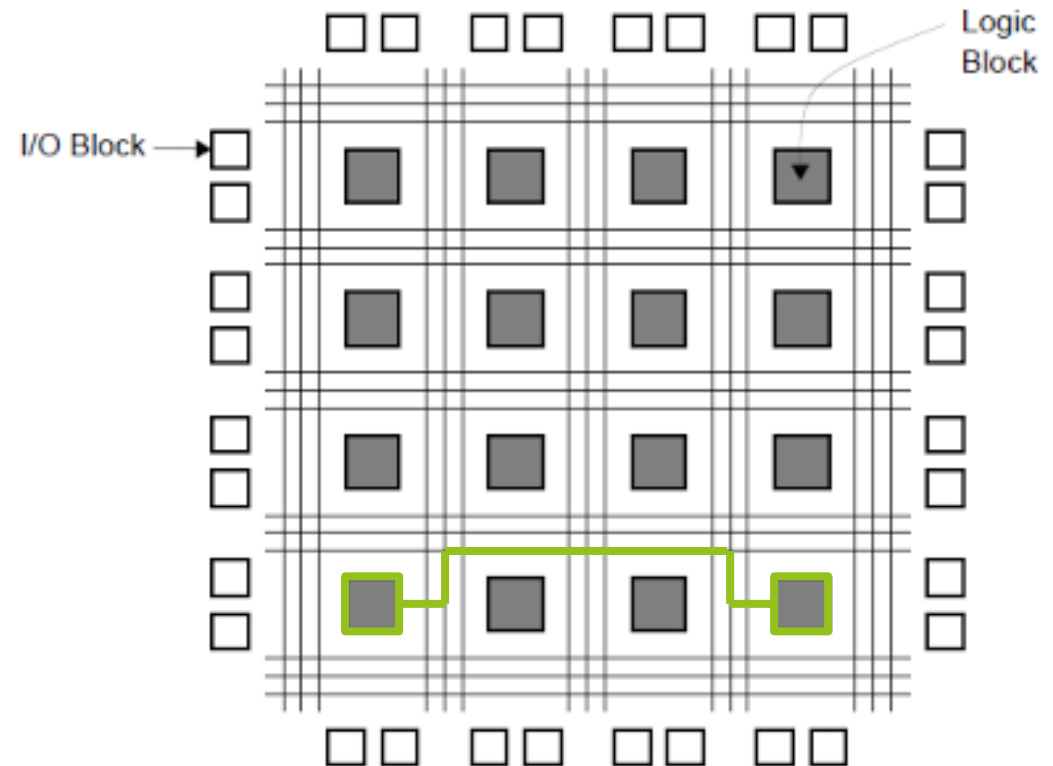
How to Duplicate?

- FPGA is organized in a grid.
- Xilinx Design Language (XDL)
- Components/PIPs are addressable via X and Y coordinates.
- Reinstantiate components/PIPs with modified coordinates.
- Change component configuration.
- Original circuit: placement constraints
- Complementary circuit: prohibit constraint



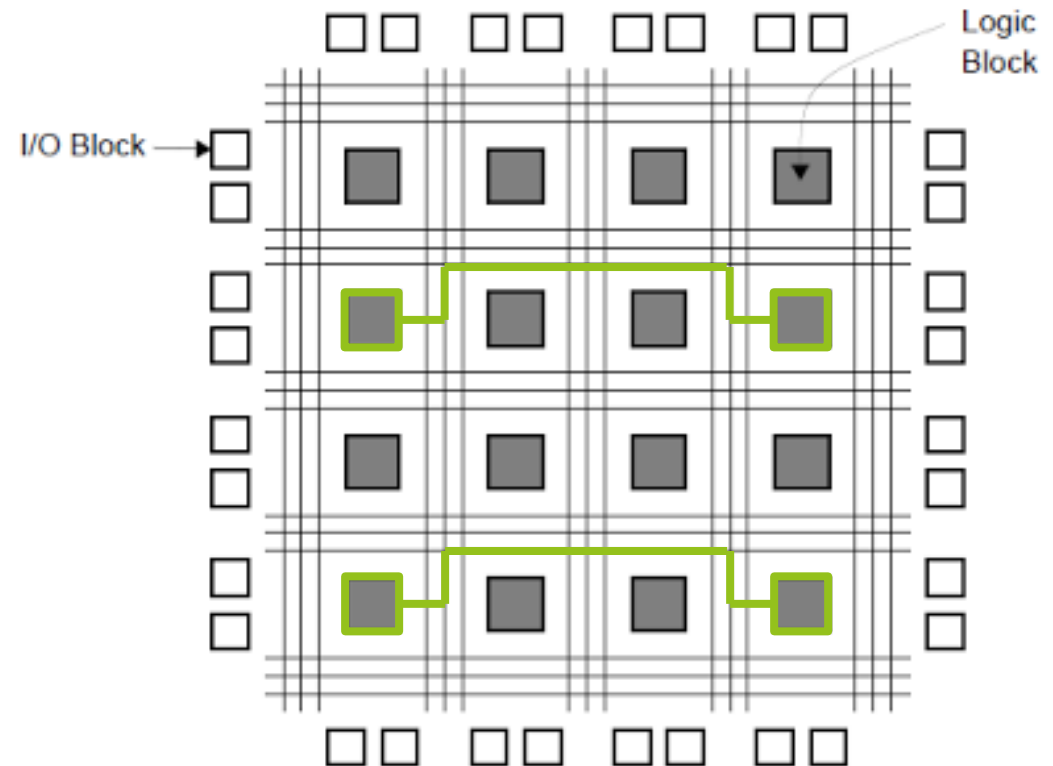
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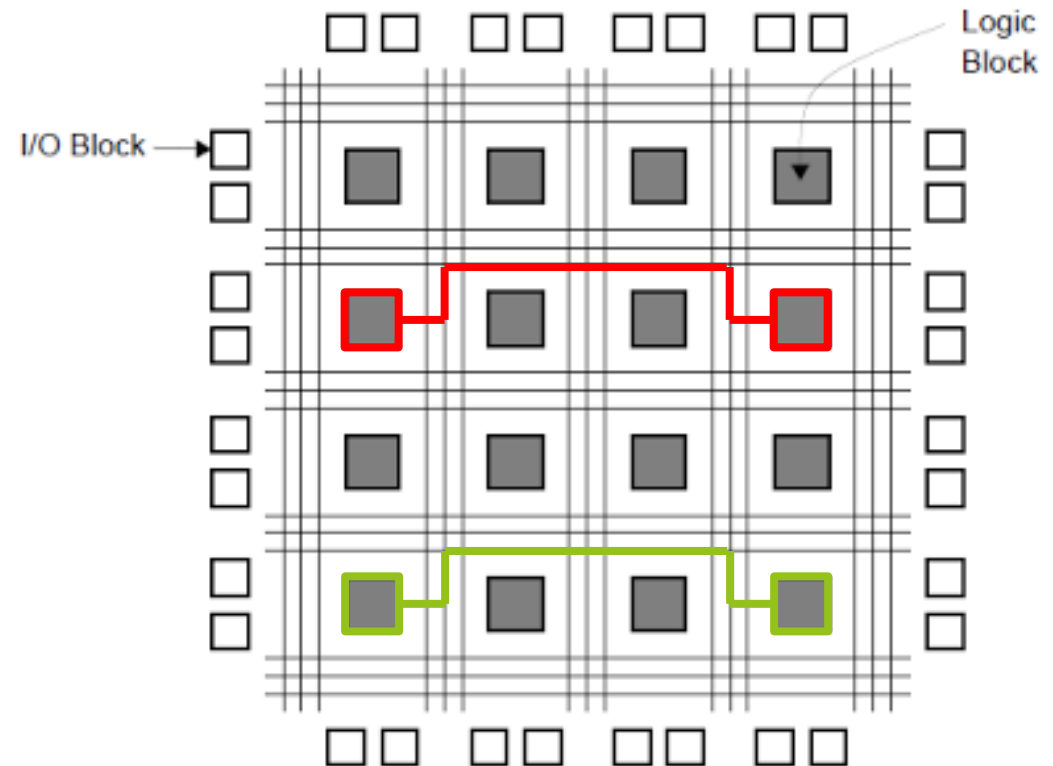
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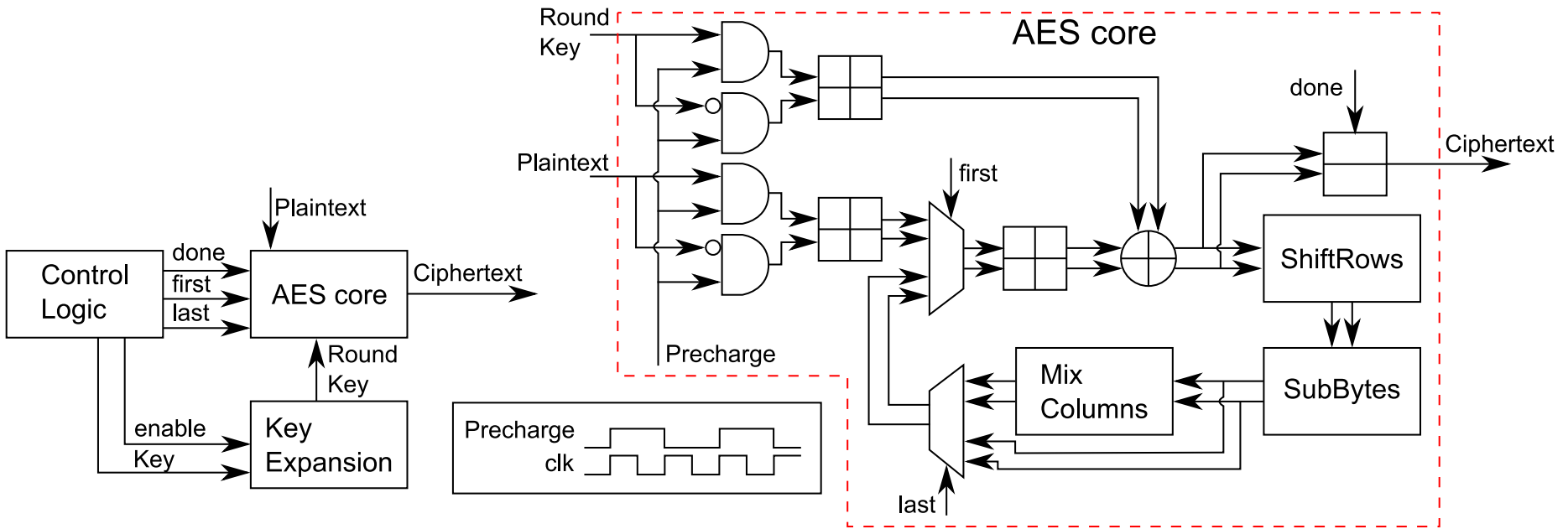


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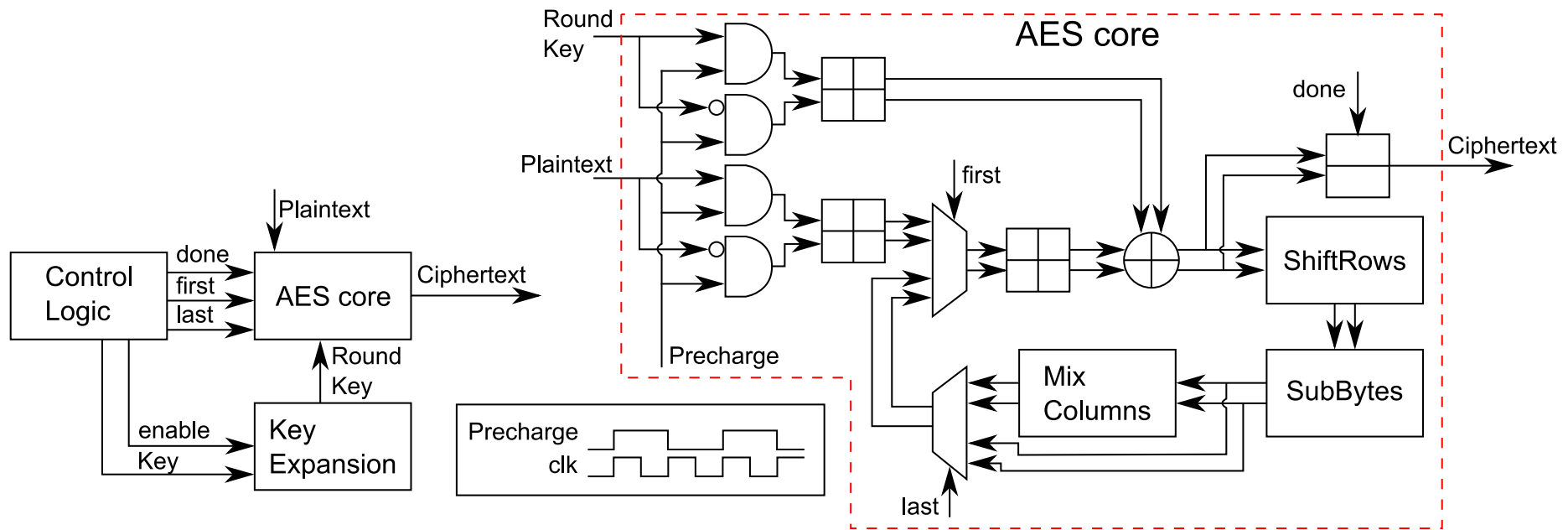
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Case Study

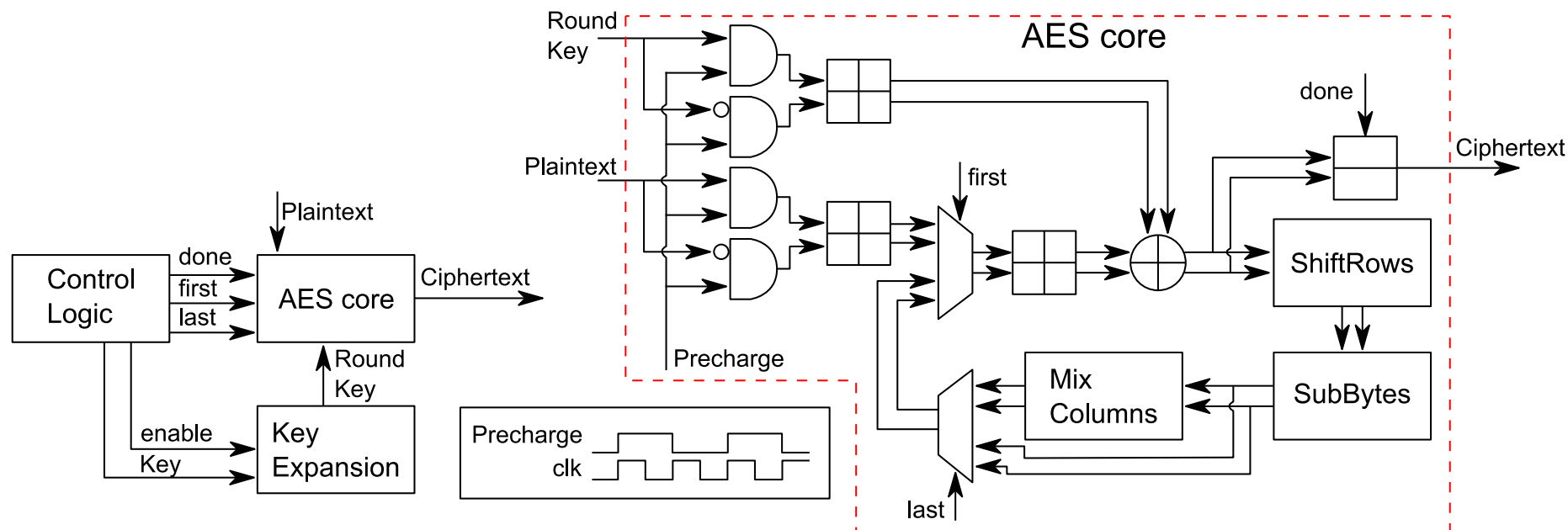


Case Study



- Round-based architecture
 - WDDL \Rightarrow DWDDL
 - DPL-noEE \Rightarrow DDPL-noEE
 - AWDDL \Rightarrow DAWDDL

Case Study

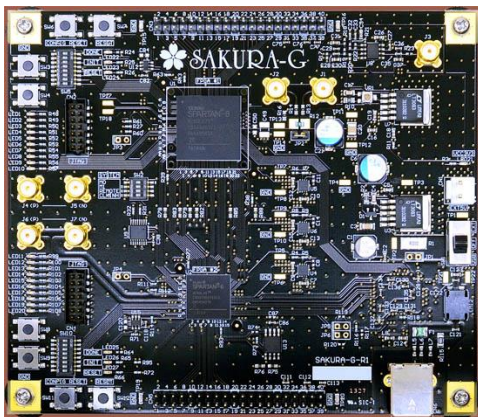


- Round-based architecture
 - WDDL \Rightarrow DWDDL
 - DPL-noEE \Rightarrow DDPL-noEE
 - AWDDL \Rightarrow DAWDDL

Logic Style	LUT	FF
WDDL	8,154	1,672
DWDDL	16,308	3,344
DPL-noEE	3,834	1,672
DDPL-noEE	7,668	3,344
AWDDL	7,146	1,672
DAWDDL	14,292	3,344

Setup

- SAKURA-G (Xilinx Spartan 6)
- 1Ω Resistor at Vdd
- 1 GS/s, 20MHz Bandwidth
- 3 MHz Clock
- 1M Traces

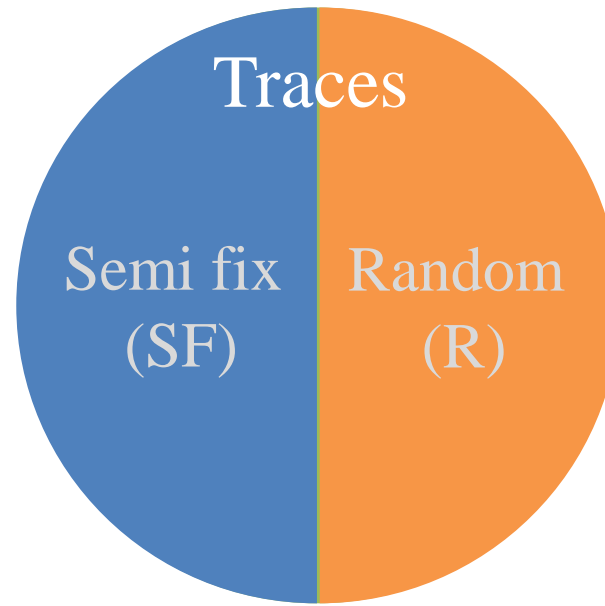


Evaluation

Welch's T-Test

Semi fix vs. random:

- 1024 plaintexts
- First 64 bits of round 5 are NULL
- Randomly picked



N_{SF} = Size of SF

X_{SF} = Mean of SF

S_{SF} = Std. deviation of SF

N_R = Size of R

X_R = Mean of R

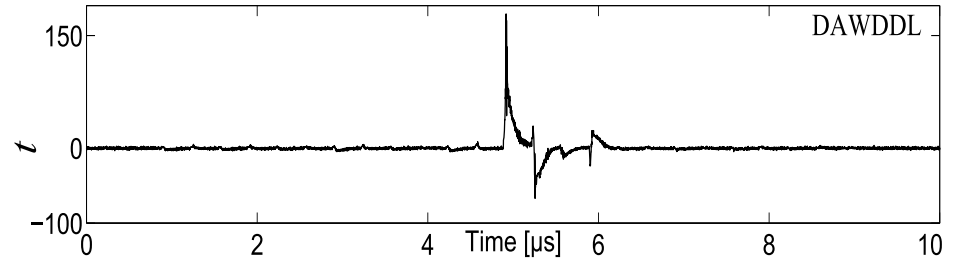
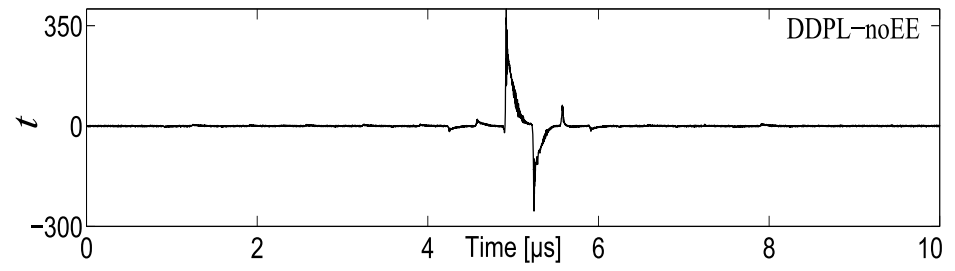
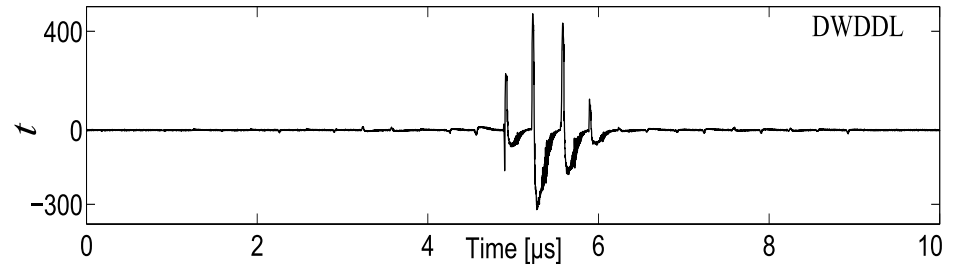
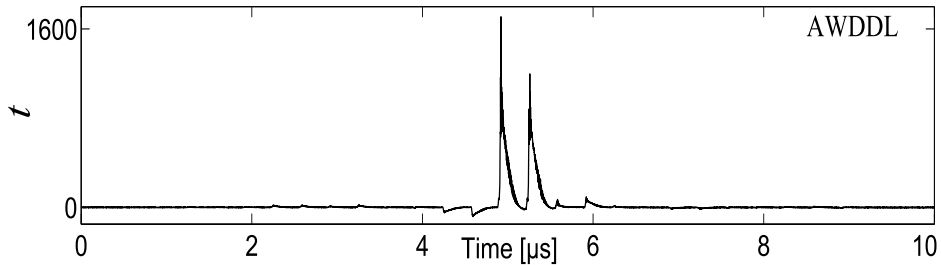
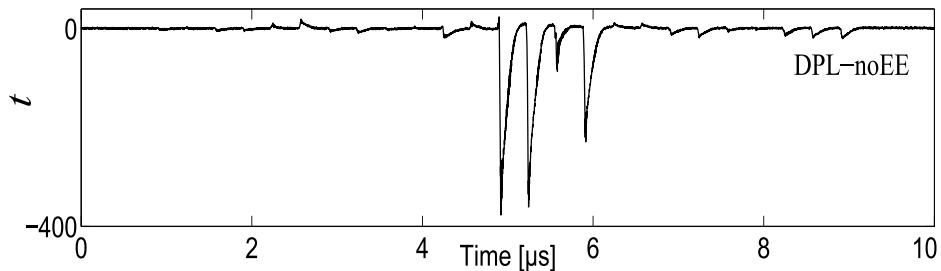
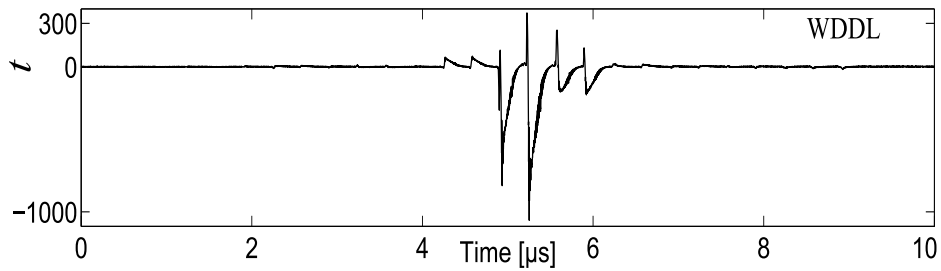
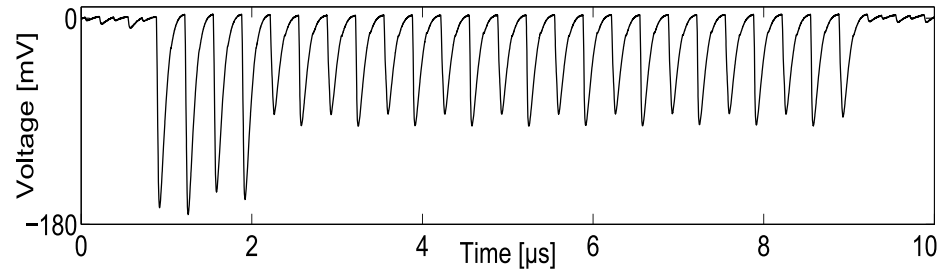
S_R = Std. deviation of R

$$T = \frac{X_{SF} - X_R}{\sqrt{\frac{S_{SF}^2}{N_{SF}} + \frac{S_R^2}{N_R}}}$$

Fail/Pass Criteria: If there is any point in time for which the t-statistic trace exceeds a threshold +/- 4.5 the device under test fails.

Evaluation

Results



Conclusions

- Dual-rail routing does not work well on FPGA (CHES 2014)
- Duplication show a data dependent time of evaluation.
 - still detectable leakage
- Not a clear future for dual-rail pre-charge logic on FPGAs
- follow-up work: (seems to be a suitable solution)
 - **GliFreD: Glitch-Free Duplication - Towards Power-Equalized Circuits on FPGAs** (ePrint 2015/124)

Thank you for Listening!

Any Questions?